

<b>Notice of References Cited</b>	Application/Control No. 10/785,445	Applicant(s)/Patent Under Reexamination WANG ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0096083	05-2003	Morgan et al.	428/141
*	C	US-6,607,994	08-2003	Soane et al.	442/59
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	K	US-			
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**NON-PATENT DOCUMENTS**

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